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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of

Keizo Yamada

Serial No.: 09/865,528

Group Art Unit: 2829

Filed: May 29, 2001

Examiner: Nguyen, Vinh P.

For: SEMICONDUCTOR DEVICE TEST METHOD AND SEMICONDUCTOR DEVICE
TESTER

Honorable Commissioner of Patents
Alexandria, VA 22313 - 1450

AMENDMENT UNDER 37 C.F.R. §1.111

Sir:

In response to the Office Action dated June 4, 2003, please amend the above-identified application as follows:

INTRODUCTORY COMMENTS

Claims 1-26 are all the claims presently pending in the application. Claims 1, 14 and 26 have been amended to more clearly define the invention. Claims 2-13 and 15-25 have been withdrawn from prosecution. Of the remaining claims, claims 1, 14 and 26 are independent.

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